

AMENDMENTS TO THE SPECIFICATION

Please amend the Specification as follows:

Please insert as new paragraph on page 1 before instant paragraph [0001]:

--CROSS-REFERENCE TO RELATED APPLICATION

This application is a National Stage entry of International Application No. PCT/JP04/15930, filed October 27, 2004, which claims priority to Japanese Patent Application No. 2003-368372, filed October 29, 2003, the disclosure of the prior applications being incorporated in their entirety by reference.--

Please replace the title preceding paragraph [0017] of the instant specification currently reading as "MEANS FOR SOLVING THE PROBLEM" with the following amended title:

BRIEF SUMMARY OF THE INVENTION

Please replace the title preceding paragraph [0017] currently reading as "BEST MODE FOR CARRYING OUT THE INVENTION" with the following amended title:

DETAILED DESCRIPTION OF THE INVENTION

Please insert the following new paragraphs between paragraphs [0022] and [0023] of the instant specification:

--BRIEF DESCRIPTION OF DRAWINGS

FIG. 1 is a skeleton schematic view showing an electron spectroscopy analytical apparatus in accordance with embodiments 1 and 2 of the present invention; and

FIG. 2 is a view showing results of an X-ray photoelectron spectroscopy analysis of carbon 1s line after irradiating a C60 ion beam to a surface of a sample by changing an accelerating voltage.--

Please delete paragraphs [0051] and [0052] as well as their title "BRIEF DESCRIPTION OF DRAWINGS."